

**Table 0-1.** Pin Configurations

Pin Name	Function
CS	Chip Select
SCK	Serial Data Clock
SI	Serial Data Input
so	Serial Data Output
GND	Ground
vcc	Power Supply
WP	Write Protect
HOLD	Suspends Serial Input
NC	No Connect

Block Write protection is enabled by programming the status register with top  $\frac{1}{4}$ , top  $\frac{1}{2}$  or entire array of write protection. Separate Program Enable and Program Disable instructions are provided for additional data protection. Hardware data protection is provided via the  $\overline{\text{WP}}$  pin to protect against inadvertent write attempts to the status register. The  $\overline{\text{HOLD}}$  pin may be used to suspend any serial communication without resetting the serial sequence.

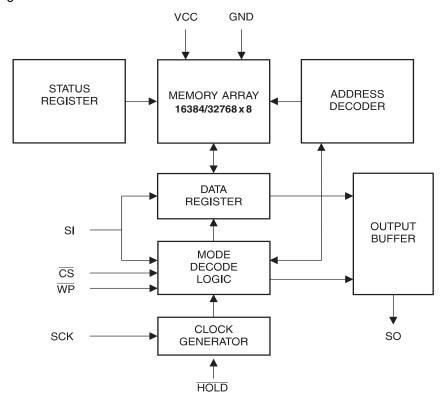
# 1. Absolute Maximum Ratings\*

Operating Temperature55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground1.0V to +7.0V
Maximum Operating Voltage
DC Output Current5.0 mA

\*NOTICE:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Figure 1-1. Block Diagram



**Table 1-1.** Pin Capacitance<sup>(1)</sup> Applicable over recommended operating range from  $T_A = 25^{\circ}C$ , f = 1.0 MHz,  $V_{CC} = +5.0$ V (unless otherwise noted)

Symbol	Test Conditions	Max	Units	Conditions
C <sub>OUT</sub>	Output Capacitance (SO)	8	pF	V <sub>OUT</sub> = 0V
C <sub>IN</sub>	Input Capacitance (CS, SCK, SI, WP, HOLD)	6	pF	V <sub>IN</sub> = 0V

Note: 1. This parameter is characterized and is not 100% tested.



Table 1-2. DC Characteristics

Applicable over recommended operating range from  $T_{AI} = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = +1.8\text{V}$  to +5.5V,

 $T_{AE} = -40$ °C to +125°C,  $V_{CC} = +1.8$ V to +5.5V(unless otherwise noted)

Symbol	Parameter	Test Condition		Min	Тур	Max	Units
V <sub>CC1</sub>	Supply Voltage		1.8		5.5	V	
V <sub>CC2</sub>	Supply Voltage			2.7		5.5	V
V <sub>CC3</sub>	Supply Voltage			4.5		5.5	V
I <sub>CC1</sub>	Supply Current	V <sub>CC</sub> = 5.0V at 20 MH Read	Hz, SO = Open,		9.0	10.0	mA
I <sub>CC2</sub>	Supply Current	V <sub>CC</sub> = 5.0V at 10 MH SO = Open, Read, N			5.0	7.0	mA
I <sub>CC3</sub>	Supply Current	V <sub>CC</sub> = 5.0V at 1 MHz SO = Open, Read, V		2.2	3.5	mA	
I <sub>SB1</sub>	Standby Current	$V_{CC} = 1.8V, \overline{CS} = V_{C}$		0.2	3.0	μΑ	
I <sub>SB2</sub>	Standby Current	$V_{CC} = 2.7V, \overline{CS} = V_{C}$		0.5	3.0	μΑ	
I <sub>SB3</sub>	Standby Current	$V_{CC} = 5.0V, \overline{CS} = V_{CC}$			2.0	5.0	μA
I <sub>IL</sub>	Input Leakage	V <sub>IN</sub> = 0V to V <sub>CC</sub>		-3.0		3.0	μΑ
I <sub>OL</sub>	Output Leakage	$V_{IN} = 0V \text{ to } V_{CC}, T_{AC}$	= 0°C to 70°C	-3.0		3.0	μΑ
V <sub>IL</sub> <sup>(1)</sup>	Input Low-voltage			-1.0		V <sub>CC</sub> x 0.3	V
V <sub>IH</sub> <sup>(1)</sup>	Input High-voltage					V <sub>CC</sub> + 0.5	V
V <sub>OL1</sub>	Output Low-voltage	0.0 < 1/ < 5.51/	I <sub>OL</sub> = 3.0 mA			0.4	V
V <sub>OH1</sub>	Output High-voltage	$3.6 \le V_{CC} \le 5.5V$	$I_{OH} = -1.6 \text{ mA}$	V <sub>CC</sub> -0.8			V
V <sub>OL2</sub>	Output Low-voltage	101/21/2001	I <sub>OL</sub> = 0.15 mA			0.2	V
V <sub>OH2</sub>	Output High-voltage	$1.8V \le V_{CC} \le 3.6V$	$I_{OH} = -100 \ \mu A$	V <sub>CC</sub> -0.2			V

Note: 1. V<sub>IL</sub> min and V<sub>IH</sub> max are reference only and are not tested.

**Table 1-3.** AC Characteristics Applicable over recommended operating range from  $T_{AI} = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $T_{AE} = -40^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = \text{As Specified}$ , CL = 1 TTL Gate and 30 pF (unless otherwise noted)

Symbol	Parameter	Voltage	Min	Max	Units
f <sub>SCK</sub>	SCK Clock Frequency	4.5–5.5 2.7–5.5	0	20 10	MHz
t <sub>RI</sub>	Input Rise Time	1.8–5.5 4.5–5.5 2.7–5.5 1.8–5.5	0	5 2 2 2 2	μs
t <sub>FI</sub>	Input Fall Time	4.5–5.5 2.7–5.5 1.8–5.5		2 2 2	μs
lwн	SCK High Time	4.5–5.5 2.7–5.5 1.8–5.5	20 40 80		ns
t <sub>wL</sub>	SCK Low Time	4.5–5.5 2.7–5.5 1.8–5.5	20 40 80		ns
t <sub>cs</sub>	CS High Time	4.5–5.5 2.7–5.5 1.8–5.5	100 100 200		ns
t <sub>css</sub>	CS Setup Time	4.5–5.5 2.7–5.5 1.8–5.5	100 100 200		ns
t <sub>CSH</sub>	CS Hold Time	4.5–5.5 2.7–5.5 1.8–5.5	100 100 200		ns
t <sub>SU</sub>	Data In Setup Time	4.5–5.5 2.7–5.5 1.8–5.5	5 10 20		ns
t <sub>H</sub>	Data In Hold Time	4.5–5.5 2.7–5.5 1.8–5.5	5 10 20		ns
t <sub>HD</sub>	Hold Setup Time	4.5–5.5 2.7–5.5 1.8–5.5	5 10 20		ns
t <sub>CD</sub>	Hold Hold Time	4.5–5.5 2.7–5.5 1.8–5.5	5 10 20		ns
t <sub>V</sub>	Output Valid	4.5–5.5 2.7–5.5 1.8–5.5	0 0 0	20 40 80	ns
t <sub>HO</sub>	Output Hold Time	4.5–5.5 2.7–5.5 1.8–5.5	0 0 0		ns
$t_LZ$	Hold to Output Low Z	4.5–5.5 2.7–5.5 1.8–5.5	0 0 0	25 50 100	ns





 Table 1-3.
 AC Characteristics (Continued)

Applicable over recommended operating range from  $T_{AI} = -40^{\circ}C$  to  $+85^{\circ}C$ ,  $T_{AE} = -40^{\circ}C$  to  $+125^{\circ}C$ ,  $V_{CC} = As$  Specified, CL = 1 TTL Gate and 30 pF (unless otherwise noted)

Symbol	Parameter	Voltage	Min	Max	Units
t <sub>HZ</sub>	Hold to Output High Z	4.5–5.5 2.7–5.5 1.8–5.5		25 50 100	ns
t <sub>DIS</sub>	Output Disable Time	4.5–5.5 2.7–5.5 1.8–5.5		25 50 100	ns
t <sub>WC</sub>	Write Cycle Time	4.5–5.5 2.7–5.5 1.8–5.5		5 5 5	ms
Endurance <sup>(1)</sup>	5.0V, 25°C, Page Mode		1M		Write Cycles

Notes: 1. This parameter is characterized and is not 100% tested. Contact Atmel for further information.

# 2. Serial Interface Description

**MASTER:** The device that generates the serial clock.

**SLAVE:** Because the serial clock pin (SCK) is always an input, the AT25128A/256A always operates as a slave.

**TRANSMITTER/RECEIVER:** The AT25128A/256A has separate pins designated for data transmission (SO) and reception (SI).

MSB: The Most Significant Bit (MSB) is the first bit transmitted and received.

**SERIAL OP-CODE:** After the device is selected with  $\overline{CS}$  going low, the first byte will be received. This byte contains the op-code that defines the operations to be performed.

**INVALID OP-CODE:** If an invalid op-code is received, no data will be shifted into the AT25128A/256A, and the serial output pin (SO) will remain in a high impedance state until the falling edge of  $\overline{CS}$  is detected again. This will reinitialize the serial communication.

**CHIP SELECT:** The AT25128A/256A is selected when the  $\overline{CS}$  pin is low. When the device is not selected, data will not be accepted via the SI pin, and the serial output pin (SO) will remain in a high impedance state.

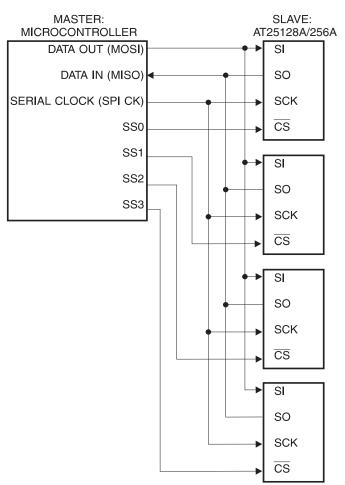
**HOLD:** The  $\overline{\text{HOLD}}$  pin is used in conjunction with the  $\overline{\text{CS}}$  pin to select the AT25128A/256A. When the device is selected and a serial sequence is underway,  $\overline{\text{HOLD}}$  can be used to pause the serial communication with the master device without resetting the serial sequence. To pause, the  $\overline{\text{HOLD}}$  pin must be brought low while the SCK pin is low. To resume serial communication, the  $\overline{\text{HOLD}}$  pin is brought high while the SCK pin is low (SCK may still toggle during  $\overline{\text{HOLD}}$ ). Inputs to the SI pin will be ignored while the SO pin is in the high impedance state.

**WRITE PROTECT:** The write protect pin  $(\overline{WP})$  will allow normal read/write operations when held high. When the  $\overline{WP}$  pin is brought low and WPEN bit is "1", all write operations to the status register are inhibited.  $\overline{WP}$  going low while  $\overline{CS}$  is still low will interrupt a write to the status register. If the internal write cycle has already been initiated,  $\overline{WP}$  going low will have no effect on any write operation to the status register. The  $\overline{WP}$  pin function is blocked when the WPEN bit in the status register is "0". This will allow the user to install the AT25128A/256A in a system with the  $\overline{WP}$  pin tied to ground and still be able to write to the status register. All  $\overline{WP}$  pin functions are enabled when the WPEN bit is set to "1".





Figure 2-1. SPI Serial Interface



# 3. Functional Description

The AT25128A/256A is designed to interface directly with the synchronous serial peripheral interface (SPI) of the 6800 type series of microcontrollers.

The AT25128A/256A utilizes an 8-bit instruction register. The list of instructions and their operation codes are contained in see Table 4-3. All instructions, addresses, and data are transferred with the MSB first and start with a high-to-low  $\overline{\text{CS}}$  transition.

**Table 3-1.** Instruction Set for the AT25128A/256A

Instruction Name	Instruction Format	Operation	
WREN	0000 X110	Set Write Enable Latch	
WRDI	0000 X100	Reset Write Enable Latch	
RDSR	0000 X101	Read Status Register	
WRSR	0000 X001	Write Status Register	
READ	0000 X011	Read Data from Memory Array	
WRITE	0000 X010	Write Data to Memory Array	

**WRITE ENABLE (WREN):** The device will power-up in the write disable state when V<sub>CC</sub> is applied. All programming instructions must therefore be preceded by a Write Enable instruction.

**WRITE DISABLE (WRDI):** To protect the device against inadvertent writes, the Write Disable instruction disables all programming modes. The WRDI instruction is independent of the status of the  $\overline{\text{WP}}$  pin.

**READ STATUS REGISTER (RDSR):** The Read Status Register instruction provides access to the status register. The Ready/Busy and Write Enable status of the device can be determined by the RDSR instruction. Similarly, the Block Write Protection bits indicate the extent of protection employed. These bits are set by using the WRSR instruction.

**Table 3-2.** Status Register Format

Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
WPEN	Х	Х	Х	BP1	BP0	WEN	RDY

**Table 3-3.** Read Status Register Bit Definition

Bit	Definition			
Bit 0 (RDY)	Bit $0 = "0" (\overline{RDY})$ indicates the device is ready. Bit $0 = "1"$ indicates the write cycle is in progress.			
Bit 1 (WEN)	Bit 1 = 0 indicates the device <i>is not</i> write enabled. Bit 1 = "1" indicates the device is write enabled.			
Bit 2 (BP0)	See Table 3-4 on page 10.			
Bit 3 (BP1)	See Table 3-4 on page 10.			
Bits 4 – 6 are 0s when device is not in an internal write cycle.				
Bit 7 (WPEN) See Table 3-5 on page 10.				
Bits 0 – 7 are "1"s du	uring an internal write cycle.			





WRITE STATUS REGISTER (WRSR): The WRSR instruction allows the user to select one of four levels of protection. The AT25128A/256A is divided into four array segments. Top quarter (1/4), top half (1/2), or all of the memory segments can be protected. Any of the data within any selected segment will therefore be read only. The block write protection levels and corresponding status register control bits are shown in Table 3-4.

The three bits, BP0, BP1, and WPEN are nonvolatile cells that have the same properties and functions as the regular memory cells (e.g. WREN, t<sub>WC</sub>, RDSR).

Table 3-4. Block Write Protect Bits

	Status Register Bits		Array Addres	ses Protected
Level	BP1	BP0	AT25128A	AT25256A
0	0	0	None	None
1(1/4)	0	1	3000 – 3FFF	6000 – 7FFF
2(1/2)	1	0	2000 – 3FFF	4000 – 7FFF
3(All)	1	1	0000 – 3FFF	0000 – 7FFF

The WRSR instruction also allows the user to enable or disable the write protect  $(\overline{WP})$  pin through the use of the write protect enable (WPEN) bit. Hardware write protection is enabled when the  $\overline{WP}$  pin is low and the WPEN bit is "1". Hardware write protection is disabled when either the  $\overline{WP}$  pin is high or the WPEN bit is "0". When the device is hardware write protected, writes to the Status Register, including the Block Protect bits and the WPEN bit, and the block-protected sections in the memory array are disabled. Writes are only allowed to sections of the memory which are not block-protected.

**NOTE:** When the WPEN bit is hardware write protected, it cannot be changed back to "0", as long as the  $\overline{WP}$  pin is held low.

Table 3-5.WPEN Operation

WPEN	WP	WEN	Protected Blocks	Unprotected Blocks	Status Register
0	Х	0	Protected	Protected	Protected
0	X	1	Protected	Writable	Writable
1	Low	0	Protected	Protected	Protected
1	Low	1	Protected	Writable	Protected
Х	High	0	Protected	Protected	Protected
Х	High	1	Protected	Writable	Writable

**READ SEQUENCE (READ):** Reading the AT25128A/256A via the SO pin requires the following sequence. After the  $\overline{CS}$  line is pulled low to select a device, the Read op-code is transmitted via the SI line followed by the byte address to be read (see Table 3-6 on page 11). Upon completion, any data on the SI line will be ignored. The data (D7 - D0) at the specified address is then shifted out onto the SO line. If only one byte is to be read, the  $\overline{CS}$  line should be driven high after the data comes out. The read sequence can be continued since the byte address is automatically incremented and data will continue to be shifted out. When the highest address is

reached, the address counter will roll over to the lowest address allowing the entire memory to be read in one continuous read cycle.

**WRITE SEQUENCE (WRITE):** In order to program the AT25128A/256A, two separate instructions must be executed. First, the device *must be write enabled* via the Write Enable (WREN) Instruction. Then a Write instruction may be executed. Also, the address of the memory location(s) to be programmed must be outside the protected address field location selected by the Block Write Protection Level. During an internal write cycle, all commands will be ignored except the RDSR instruction.

A Write Instruction requires the following sequence. After the  $\overline{\text{CS}}$  line is pulled low to select the device, the Write op-code is transmitted via the SI line followed by the byte address and the data (D7 - D0) to be programmed (see Table 3-6). Programming will start after the  $\overline{\text{CS}}$  pin is brought high. (The Low-to-High transition of the  $\overline{\text{CS}}$  pin must occur during the SCK low time immediately after clocking in the D0 (LSB) data bit.

The Ready/Busy status of the device can be determined by initiating a Read Status Register (RDSR) Instruction. If Bit 0 = 1, the Write cycle is still in progress. If Bit 0 = 0, the Write cycle has ended. Only the Read Status Register instruction is enabled during the Write programming cycle.

The AT25128A/256A is capable of a 64-byte Page Write operation. After each byte of data is received, the six low order address bits are internally incremented by one; the high order bits of the address will remain constant. If more than 64 bytes of data are transmitted, the address counter will roll over and the previously written data will be overwritten. The AT25128A/256A is automatically returned to the write disable state at the completion of a Write cycle.

**NOTE:** If the device is not write enabled (WREN), the device will ignore the Write instruction and will return to the standby state, when  $\overline{CS}$  is brought high. A new CS falling edge is required to re-initiate the serial communication.

Table 3-6. Address Key

Address	AT25128A	AT25256A
A <sub>N</sub>	$A_{13} - A_0$	$A_{14} - A_0$
Don't Care Bits	A <sub>15</sub> – A <sub>14</sub>	A <sub>15</sub>





# 4. Timing Diagrams (for SPI Mode 0 (0, 0))

Figure 4-1. Synchronous Data Timing

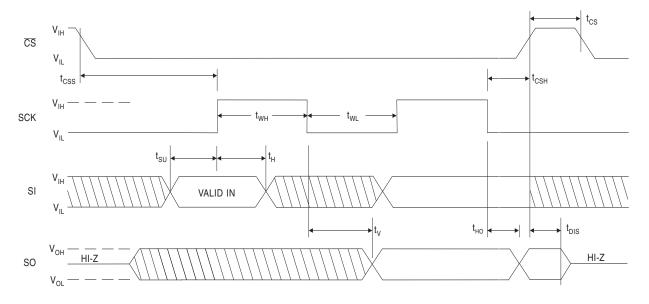
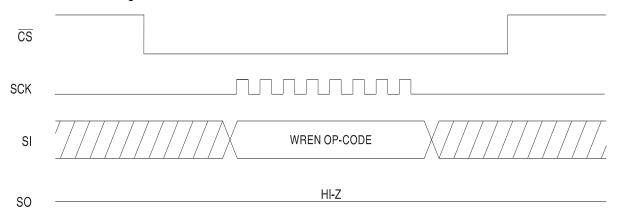


Figure 4-2. WREN Timing





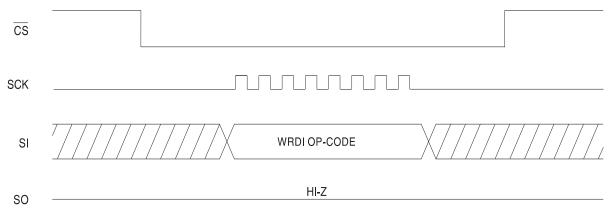


Figure 4-4. RDSR Timing

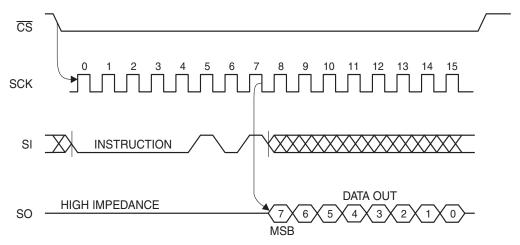


Figure 4-5. WRSR Timing

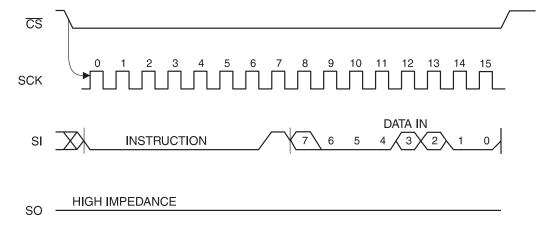






Figure 4-6. READ Timing

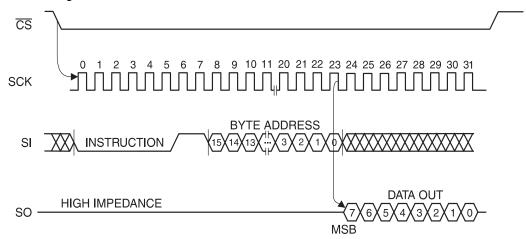


Figure 4-7. WRITE Timing

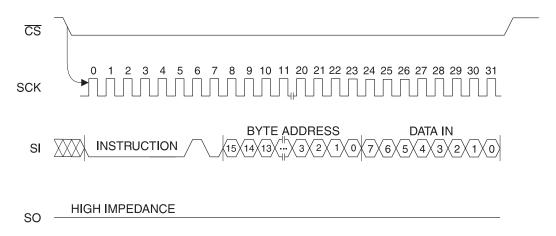
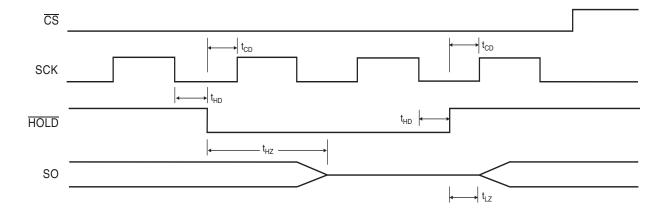


Figure 4-8. HOLD Timing



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# 5. AT25128A Ordering Information<sup>(1)</sup>

Ordering Code	Package	Operation Range
AT25128A-10PU-2.7 <sup>(2)</sup>	8P3	
AT25128A-10PU-1.8 <sup>(2)</sup>	8P3	
AT25128AN-10SU-2.7 <sup>(2)</sup>	8S1	
AT25128AN-10SU-1.8 <sup>(2)</sup>	8S1	Lood fron / Lologon fron /
AT25128AW-10SU-2.7 <sup>(2)</sup>	8S2	Lead-free/Halogen-free/
AT25128AW-10SU-1.8 <sup>(2)</sup>	8S2	Industrial Temperature
AT25128A-10TU-2.7 <sup>(2)</sup>	8A2	(-40°C to 85°C)
AT25128A-10TU-1.8 <sup>(2)</sup>	8A2	
AT25128AU2-10UU-1.8 <sup>(2)</sup>	8U2-1	
AT25128AY7-10YH-1.8 <sup>(2)</sup>	8Y7	
AT25128A-W1.8-11 <sup>(3)</sup>	Die Sale	Industrial Temperature
A120120A-W1.0-1117	Die Sale	(-40°C to 85°C)

Notes:

- 1. For 2.7V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC Characteristics tables.
- 2. "U" designates Green package + RoHS compliant.
- 3. Available in waffle pack and wafer form; order as SL788 for wafer form. Bumped die available upon request. Please Contact Serial Interface Marketing.

Package Type		
8P3	8-lead, 0.300" Wide, Plastic Dual In-line Package (PDIP)	
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline Package (JEDEC SOIC)	
8S2	8-lead, 0.200" Wide, Plastic Gull Wing Small Outline Package (EIAJ SOIC)	
8U2-1	8-ball, die Ball Grid Array Package (dBGA2)	
8A2	8-lead, 4.4 mm Body, Thin Shrink Small Outline Package (TSSOP)	
8Y7	8-lead, 6.00 mm x 4.90 mm Body, Ultra Thin, Dual Footprint, Non-leaded, Small Array Package (SAP)	
Options		
-2.7	Low-voltage (2.7V to 5.5V)	
-1.8	Low-voltage (1.8V to 5.5V)	





# AT25256A Ordering Information<sup>(1)</sup>

Ordering Code	Package	Operation Range
AT25256A-10PU-2.7 <sup>(2)</sup>	8P3	
AT25256A-10PU-1.8 <sup>(2)</sup>	8P3	
AT25256AN-10SU-2.7 <sup>(2)</sup>	8S1	
AT25256AN-10SU-1.8 <sup>(2)</sup>	8S1	Load froe/Halogan froe/
AT25256AW-10SU-2.7 <sup>(2)</sup>	8S2	Lead-free/Halogen-free/
AT25256AW-10SU-1.8 <sup>(2)</sup>	8S2	Industrial Temperature
AT25256A-10TU-2.7 <sup>(2)</sup>	8A2	(-40°C to 85°C)
AT25256A-10TU-1.8 <sup>(2)</sup>	8A2	
AT25256AU2-10UU-1.8 <sup>(2)</sup>	8U2-1	
AT25256AY7-10YH-1.8 <sup>(2)</sup>	8Y7	
AT25256A-W1.8-11 <sup>(3)</sup>	Die Sale	Industrial Temperature
	Die Sale	(-40°C to 85°C)

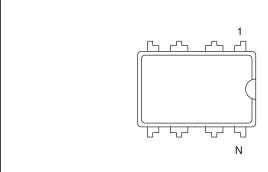
Notes:

- 1. For 2.7V devices used in the 4.5V to 5.5V range, please refer to performance values in the AC and DC Characteristics tables.
- 2. "U" designates Green package + RoHS compliant.
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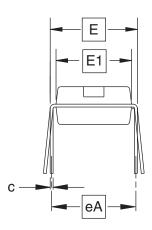
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8A2	8-lead, 4.4 mm Body, Thin Shrink Small Outline Package (TSSOP)	
8Y7	8-lead, 6.00 mm x 4.90 mm Body, Ultra Thin, Dual Footprint, Non-leaded, Small Array Package (SAP)	
Options		
-2.7	Low-voltage (2.7V to 5.5V)	
-1.8	Low-voltage (1.8V to 5.5V)	

# 6. Packaging Information

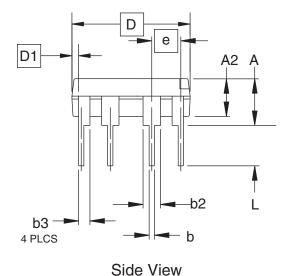
### **8P3 - PDIP**



Top View



**End View** 



#### **COMMON DIMENSIONS**

(Unit of Measure = inches)

SYMBOL	MIN	NOM	MAX	NOTE
Α	_	_	0.210	2
A2	0.115	0.130	0.195	
b	0.014	0.018	0.022	5
b2	0.045	0.060	0.070	6
b3	0.030	0.039	0.045	6
С	0.008	0.010	0.014	
D	0.355	0.365	0.400	3
D1	0.005	_	_	3
Е	0.300	0.310	0.325	4
E1	0.240	0.250	0.280	3
е	0.100 BSC			
eA	0.300 BSC		4	
L	0.115	0.130	0.150	2

Notes:

- 1. This drawing is for general information only; refer to JEDEC Drawing MS-001, Variation BA, for additional information.
- 2. Dimensions A and L are measured with the package seated in JEDEC seating plane Gauge GS-3.
- 3. D, D1 and E1 dimensions do not include mold Flash or protrusions. Mold Flash or protrusions shall not exceed 0.010 inch.
- 4. E and eA measured with the leads constrained to be perpendicular to datum.
- 5. Pointed or rounded lead tips are preferred to ease insertion.
- 6. b2 and b3 maximum dimensions do not include Dambar protrusions. Dambar protrusions shall not exceed 0.010 (0.25 mm).

01/09/02



2325 Orchard Parkway San Jose, CA 95131

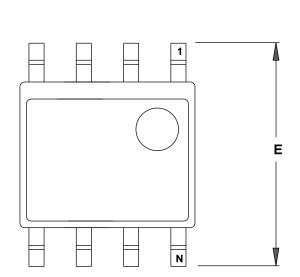
IIILE
8P3, 8-lead, 0.300" Wide Body, Plastic Dual
In-line Package (PDIP)

DRAWING NO.	REV.
8P3	В

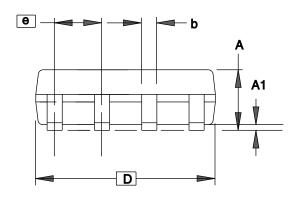




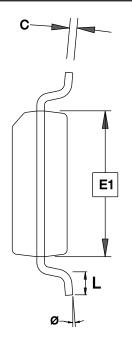
# **8S1 - JEDEC SOIC**



**TOP VIEW** 



**SIDE VIEW** 



**END VIEW** 

# **COMMON DIMENSIONS** (Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	1.35	-	1.75	
A1	0.10	_	0.25	
b	0.31	_	0.51	
С	0.17	_	0.25	
D	4.80	-	5.05	
E1	3.81	_	3.99	
E	5.79	_	6.20	
е	1.27 BSC			
L	0.40	_	1.27	
θ	0°	_	8°	

Note: These drawings are for general information only. Refer to JEDEC Drawing MS-012, Variation AA for proper dimensions, tolerances, datums, etc.

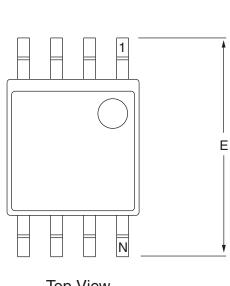
3/17/05

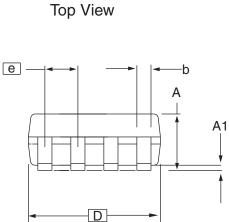
<u>AMEL</u>

1150 E. Cheyenne Mtn. Blvd. Colorado Springs, CO 80906 **TITLE 8S1**, 8-lead (0.150" Wide Body), Plastic Gull Wing Small Outline (JEDEC SOIC)

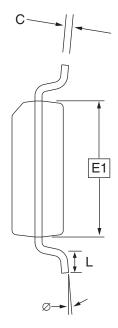
BS1 REV.

### 8S2 - EIAJ SOIC





Side View



**End View** 

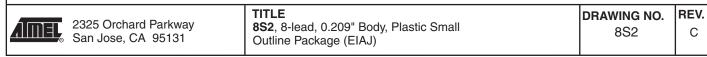
#### **COMMON DIMENSIONS** (Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	1.70		2.16	
A1	0.05		0.25	
b	0.35		0.48	5
С	0.15		0.35	5
D	5.13		5.35	
E1	5.18		5.40	2, 3
E	7.70		8.26	
L	0.51		0.85	
Ø	0°		8°	
е		1.27 BSC		4

- Notes: 1. This drawing is for general information only; refer to EIAJ Drawing EDR-7320 for additional information.
  2. Mismatch of the upper and lower dies and resin burrs are not included.

  - 3. It is recommended that upper and lower cavities be equal. If they are different, the larger dimension shall be regarded.
  - 4. Determines the true geometric position.
  - 5. Values b and C apply to pb/Sn solder plated terminal. The standard thickness of the solder layer shall be 0.010 +0.010/-0.005 mm.

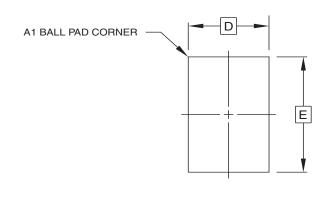
10/7/03





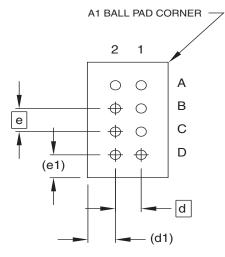


# 8U2-1 - dBGA2





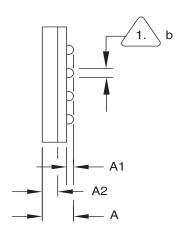
Top View



Bottom View 8 Solder Balls

1. Dimension 'b' is measured at the maximum solder ball diameter.

This drawing is for general information only.



Side View

### COMMON DIMENSIONS

(Unit of Measure = mm)

SYMBOL	MIN	NOM	MAX	NOTE
Α	0.81	0.91	1.00	
A1	0.15	0.20	0.25	
A2	0.40	0.45	0.50	
b	0.25	0.30	0.35	1
D	2.35 BSC			
Е	3.73 BSC			
е	0.75 BSC			
e1	0.74 REF			
d	0.75 BSC			
d1		0.80 REF		

6/24/03



1150 E. Cheyenne Mtn. Blvd. Colorado Springs, CO 80906 TITLE

**8U2-1,** 8-ball, 2.35 x 3.73 mm Body, 0.75 mm pitch, Small Die Ball Grid Array Package (dBGA2)

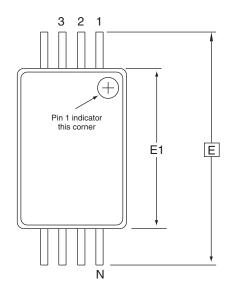
DRAWING NO.
PO8U2-1

NO. REV.

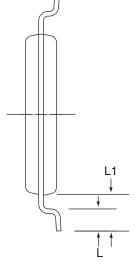
3368J-SEEPR-06/07

20

### **8A2 - TSSOP**



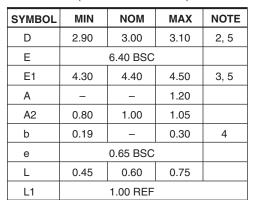
Top View

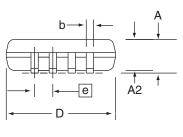


**End View** 

#### **COMMON DIMENSIONS**

(Unit of Measure = mm)





Side View

- Notes: 1. This drawing is for general information only. Refer to JEDEC Drawing MO-153, Variation AA, for proper dimensions, tolerances, datums, etc.
  - 2. Dimension D does not include mold Flash, protrusions or gate burrs. Mold Flash, protrusions and gate burrs shall not exceed 0.15 mm (0.006 in) per side.
  - 3. Dimension E1 does not include inter-lead Flash or protrusions. Inter-lead Flash and protrusions shall not exceed 0.25 mm (0.010 in) per side.
  - 4. Dimension b does not include Dambar protrusion. Allowable Dambar protrusion shall be 0.08 mm total in excess of the b dimension at maximum material condition. Dambar cannot be located on the lower radius of the foot. Minimum space between protrusion and adjacent lead is 0.07 mm.
  - 5. Dimension D and E1 to be determined at Datum Plane H.

5/30/02



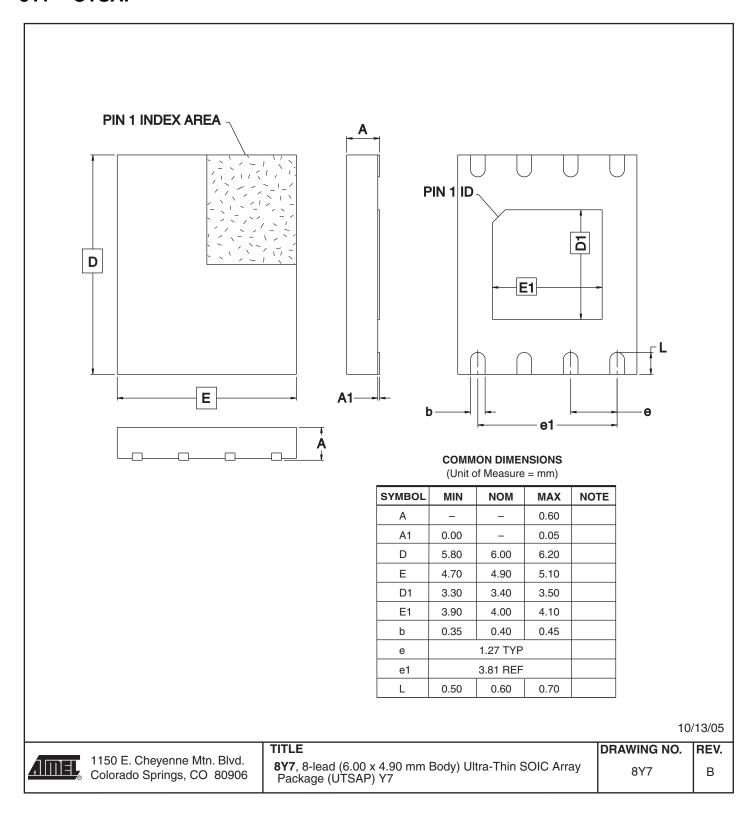
2325 Orchard Parkway San Jose, CA 95131

DRAWING NO.	REV.
8A2	В





# **8Y7 - UTSAP**



# **Revision History**

Doc. Rev.	Date	Comments
3368J	6/2007	Changed 8Y4 to 8Y7 package
33681	3/2007	Revision history implemented
		Removed Pb product offering





#### Headquarters

Atmel Corporation

2325 Orchard Parkway San Jose, CA 95131 USA

Tel: 1(408) 441-0311 Fax: 1(408) 487-2600

#### International

Atmel Asia

Room 1219 Chinachem Golden Plaza 77 Mody Road Tsimshatsui East Kowloon Hong Kong Tel: (852) 2721-9778

Fax: (852) 2722-1369

Atmel Europe

Le Krebs 8, Rue Jean-Pierre Timbaud BP 309 78054 Saint-Quentin-en-Yvelines Cedex France

Tel: (33) 1-30-60-70-00 Fax: (33) 1-30-60-71-11

Atmel Japan

9F, Tonetsu Shinkawa Bldg. 1-24-8 Shinkawa Chuo-ku, Tokyo 104-0033 Japan

Tel: (81) 3-3523-3551 Fax: (81) 3-3523-7581

#### **Product Contact**

Web Site

www.atmel.com

Technical Support

s\_eeprom@atmel.com

Sales Contact

www.atmel.com/contacts

Literature Requests
www.atmel.com/literature

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